

12/8/04-1062

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. 455610-2590.1		SERIAL NO. 10/673,736	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Martin MILLER et al.			
				FILING DATE September 29, 2003		GROUP 2117	
U.S. PATENT DOCUMENTS				Examiner: Phung M. Chung			
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
IPC/	AA	5,654,987	08/05/97	Nakamura			
	AB	5,726,607	03/10/98	Brede et al			
	AC	5,825,825	10/20/98	Altmann et al			
	AD	5,900,755	05/04/99	Toeppen et al			
	AE	6,215,363	04/10/01	Conte et al			
	AF	6,295,327	09/25/01	Takla			
	AG	6,445,230	09/03/02	Rupp et al			
	AH	4,680,778	07/14/87	Krinoek			
	AI	5,943,378	08/24/99	Keba et al			
	AJ	6,188,737	02/13/01	Bruce et al			
	AK	5,914,592	06/22/99	Saito			
	AL	5,789,954	08/04/98	Toeppen et al			
IPC/	AM	4,694,244 09-15-1987	08/15/87	Whiteside et al			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
IPC/	AN	JP4105070	04/07/92	Japan			Abstract
	AO	JP5196641 ✓	08/06/93	Japan			Abstract
	AP	JP5264595 ✓	10/12/93	Japan			Abstract
	AQ	JP8220144	06/22/99	Japan			Abstract
	AR	JP9005362 ✓	01/10/97	Japan			Abstract
	AS	JP10163859 ✓	06/19/98	Japan			Abstract
	AT	JP11098876 ✓	04/09/99	Japan			Abstract
	AU	JP62003544 ✓	01/09/87	Japan			Abstract
	AV	EP 0 631 143 ✓	12/28/94	Europe			✓
IPC/	AW	EP 0 241 142 ✓	10/14/87	Europe			✓
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
IPC/	AY	✓	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3rd Edition, McGraw-Hill, New York, 1997, pp 229-249				
	AZ	✓	Using FPGAs for Digital Applications, Actel Corporation, April 1996				
	BA	✓	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999				
	BB	✓	Infinium DCA, Agilent Technologies, March 7, 2002				
IPC/	BC	✓	Communication waveform measurements, Hewlett Packard, June 26, 1996				
EXAMINER /Phung Chung/				DATE CONSIDERED 10/11/2007			
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							



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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	3 449 671	06/1969	Long Gordon D.			
	AB	3 778 550	12/1973	David et al.			
	AC	4 375 694	03/1983	Kuhn, William B.			
	AD	4 964 117	10/1990	Shier, John S.			
	AE	6 738 992 <b>922</b>	05/2004	Warwar et al.			
	AF	2004 0123208	06/2004	Miller et al.			
	AG	2004 0153883	08/2004	Miller et al.			
	AH	3, 562 710	2/9/1971	Halleck, Michael E.			
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	AK	5,159,609	10/27/1992	Palicot			
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	AM	5,907,587	5/25/1999	Sokoler			
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	AO	6,675,328	1/6/2004	Krishnamachari			
	AP	6 850 852	02/2005	Ferguson et al.			
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	AR	2002 0128787 A1	09/2002	Seng et al.			

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ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /PC/

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	AV	2002 0034337 A1	03/2002	Shekter, Jonathan Martin			
	AW	2002 0018572 A1	02/2002	Rhoads, Geoffrey B.			
	AX	6 853 696	02/2005	Moser et al.			
	AY	2001 0021151	09/2001	Verboom, Johannes et al.			
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	BC	2004 0123191 A1	06/2004	Salant et al.			
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	BF	3 778 550	12/1973	David et al.			
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	BL	DE 2462046 A1	11/1975	Germany			
	BM	WO 2004 032049 A2	04/2004	PCT			
	BN	GB 2 138 575 A	10/24/1984	United Kingdom			

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